

# CBCS SCHEME



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15EC63

Sixth Semester B.E. Degree Examination, June/July 2023

## VLSI Design

Time: 3 hrs.

Max. Marks: 80

Note: Answer any FIVE full questions, choosing ONE full question from each module.

### Module-1

- 1 a. Derive the CMOS inverter DC characteristics graphically from p device and n device characteristics and show all operating regions. (08 Marks)
- b. Explain the working of nMOS enhancement mode transistor with suitable diagrams. (08 Marks)

OR

- 2 a. Derive expression for drain current in linear and saturation region for nMOS transistor. (08 Marks)
- b. With neat sketches explain the CMOS P-well process steps to fabricate a CMOS inverter. (08 Marks)

### Module-2

- 3 a. Discuss the CMOS design style with a diagram. (05 Marks)
- b. Draw the stick diagram for the following using CMOS logic :
  - i)  $Y = \overline{A + B + C}$
  - ii) 2 i/p NAND gate. (05 Marks)
- c. Discuss the different contact cuts with an example to each. (06 Marks)

OR

- 4 a. With a diagram derive an expression for sheet resistance and mention the  $R_s$  values of metal, p and n transistor channels for 5  $\mu\text{m}$  technology. (05 Marks)
- b. Derive an equation for rise time and fall time with respect to CMOS inverter. (08 Marks)
- c. Draw the circuit and stick diagram for 2 i/p NOR gate using CMOS logic. (03 Marks)

### Module-3

- 5 a. Design 4bit,  $4 \times 4$  barrel shifter. Write the nMOS implementation and strategy for the same. (08 Marks)
- b. Explain Carry select adder with neat block diagram. (08 Marks)

OR

- 6 a. Define Regularity. (02 Marks)
- b. Derive the scaling factor for the device parameter :
  - i) Parasitic capacitance
  - ii) Channel resistance
  - iii) Gate delay. (06 Marks)
- c. Implement the ALU functions like EX – OR, EX – NOR AND and OR operations with an adder. Write the block diagram of 4 – bit ALU using adder element. (08 Marks)

### Module-4

- 7 a. Discuss the programmable logic array with its structure and floor plan. (05 Marks)
- b. Discuss the architectural issues related to VLSI sub system design. (06 Marks)
- c. Discuss the design of Data selectors. (05 Marks)

OR

- 8 a. Explain the architecture of field programmable gate array. (10 Marks)  
b. Discuss the FPGA abstractions with a diagram. (06 Marks)

Module-5

- 9 a. Explain 3 transistor dynamic RAM cell with schematic diagram. (06 Marks)  
b. Explain any two fault models in combinational circuits. (06 Marks)  
c. Write a note on automatic test pattern generation. (04 Marks)

OR

- 10 a. Write short notes on :  
i) Observability and Controllability. (08 Marks)  
ii) Built In Self Test (BIST). (08 Marks)  
b. Explain nMOS pseudo static RAM cell with schematic diagram. (08 Marks)

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